

FQA62N25C

250V N-Channel MOSFET

General Description

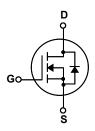
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters and switch mode power supplies.

Features

- 62A, 250V, $R_{DS(on)}$ = 0.035 Ω @V_{GS} = 10 V Low gate charge (typical 100 nC)
- Low Crss (typical 63.5 pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

| Symbol | Parameter | | FQA62N25C | Units |
|-----------------------------------|--|----------|-------------|-------|
| V_{DSS} | Drain-Source Voltage | | 250 | V |
| I _D | Drain Current - Continuous (T _C = 25° | °C) | 62 | Α |
| | - Continuous (T _C = 100°C) | | 39 | Α |
| I _{DM} | Drain Current - Pulsed | (Note 1) | 248 | Α |
| V _{GSS} | Gate-Source Voltage | | ± 30 | V |
| E _{AS} | Single Pulsed Avalanche Energy | (Note 2) | 2300 | mJ |
| I _{AR} | Avalanche Current | (Note 1) | 62 | Α |
| E _{AR} | Repetitive Avalanche Energy | (Note 1) | 29.8 | mJ |
| dv/dt | Peak Diode Recovery dv/dt | (Note 3) | 5.5 | V/ns |
| P_{D} | Power Dissipation (T _C = 25°C) | | 298 | W |
| | - Derate above 25°C | | 2.38 | W/°C |
| T _J , T _{STG} | Operating and Storage Temperature Range | | -55 to +150 | °C |
| T. | T _L Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds | | 300 | °C |
| . L | | | 300 | |

Thermal Characteristics

| Symbol | Parameter | Тур | Max | Units |
|-----------------|---|------|------|-------|
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case | | 0.42 | °C/W |
| $R_{\theta CS}$ | Thermal Resistance, Case-to-Sink | 0.24 | | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient | | 40 | °C/W |

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Units |
|---|---|---|-----|-------|-------|-------|
| Off Cha | aracteristics | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$ | 250 | | | V |
| ΔBV _{DSS} / ΔΤ _J | Breakdown Voltage Temperature Coefficient | I _D = 250 μA, Referenced to 25°0 | | 0.28 | | V/°C |
| I _{DSS} | | V _{DS} = 250 V, V _{GS} = 0 V | | | 10 | μΑ |
| | Zero Gate Voltage Drain Current | V _{DS} = 200 V, T _C = 125°C | | | 100 | μΑ |
| I _{GSSF} | Gate-Body Leakage Current, Forward | V _{GS} = 30 V, V _{DS} = 0 V | | | 100 | nA |
| I _{GSSR} | Gate-Body Leakage Current, Reverse | V _{GS} = -30 V, V _{DS} = 0 V | | | -100 | nA |
| On Cha | racteristics | | | | | |
| V _{GS(th)} | Gate Threshold Voltage | V _{DS} = V _{GS} , I _D = 250 μA | 2.0 | | 4.0 | V |
| R _{DS(on)} | Static Drain-Source On-Resistance | V _{GS} =10 V, I _D =31 A | | 0.029 | 0.035 | Ω |
| 9 _{FS} | Forward Transconductance | V _{DS} = 40 V, I _D = 31 A (Note | 4) | 55 | | S |
| Dynam C _{iss} | ic Characteristics Input Capacitance | V 05 V V 0 V | | 4830 | 6280 | pF |
| Coss | Output Capacitance | $V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz | | 945 | 1230 | рF |
| C _{rss} | Reverse Transfer Capacitance | | | 63.5 | 83 | pF |
| 155 | | | | | | le. |
| Switchi | ng Characteristics | | | | | |
| t _{d(on)} | Turn-On Delay Time | V_{DD} = 125 V, I_{D} = 62 A, R_{G} = 25 Ω | | 75 | 160 | ns |
| t _r | Turn-On Rise Time | | | 395 | 800 | ns |
| $t_{d(off)}$ | Turn-Off Delay Time | | | 245 | 500 | ns |
| t _f | Turn-Off Fall Time | (Note | 4) | 335 | 680 | ns |
| Qg | Total Gate Charge | V _{DS} = 200 V, I _D = 62 A, | | 100 | 130 | nC |
| Q _{gs} | Gate-Source Charge | V _{GS} = 10 V (Note 4) | | 25.5 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 39 | | nC |
| Drain S | Source Diode Characteristics a | nd Maximum Patings | | | | |
| I _S | Maximum Continuous Drain-Source Did | <u>~</u> | | | 62 | Α |
| I _{SM} | Maximum Pulsed Drain-Source Diode Forward Current | | | | 248 | Α |
| V _{SD} | Drain-Source Diode Forward Voltage | V _{GS} = 0 V, I _S = 62 A | | | 1.5 | V |
| t _{rr} | Reverse Recovery Time | $V_{GS} = 0 \text{ V}, I_S = 62 \text{ A},$ | | 340 | | ns |
| Q _{rr} | Reverse Recovery Charge | $dI_F / dt = 100 \text{ A/}\mu\text{s} $ (Note | | 4.77 | | μС |

- **Notes:** 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.96mH, I $_{AS}$ = 62A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C 3. I $_{SD}$ ≤ 62A, di/dt ≤ 300A/ μ s, V $_{DD}$ ≤ BV $_{DSS}$, Starting T $_{J}$ = 25°C 4. Pulse Test : Pulse width ≤ 300 μ s, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

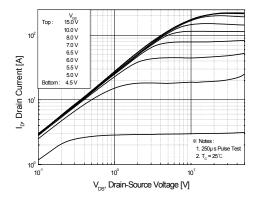


Figure 1. On-Region Characteristics

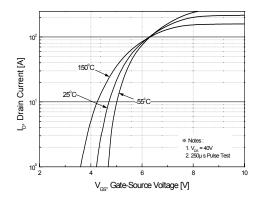


Figure 2. Transfer Characteristics

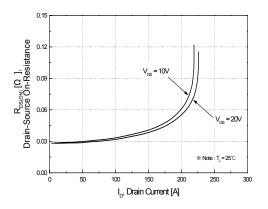


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

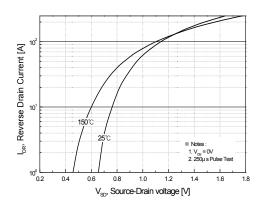


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

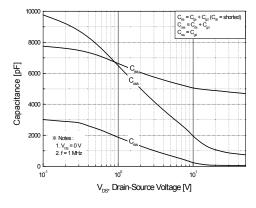


Figure 5. Capacitance Characteristics

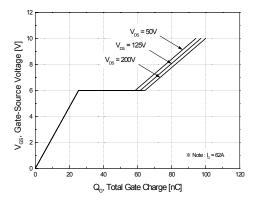


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

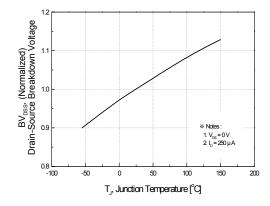


Figure 7. Breakdown Voltage Variation vs Temperature

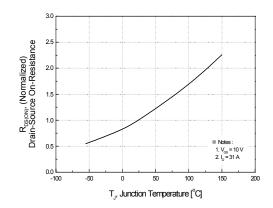


Figure 8. On-Resistance Variation vs Temperature

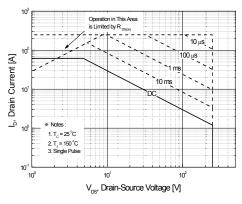


Figure 9. Maximum Safe Operating Area

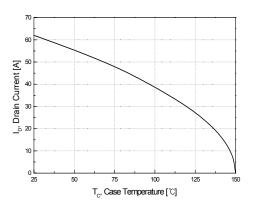


Figure 10. Maximum Drain Current vs Case Temperature

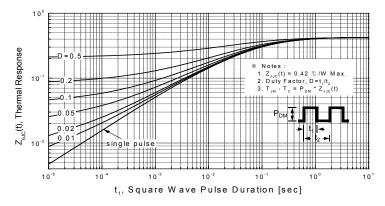
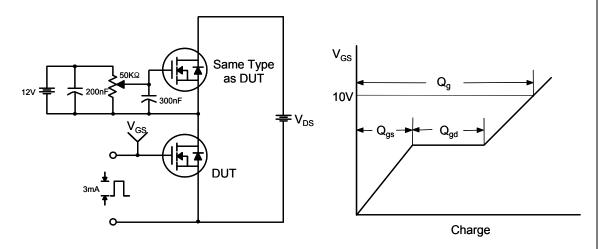


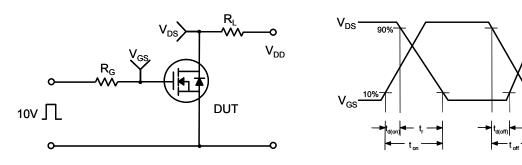
Figure 11. Transient Thermal Response Curve

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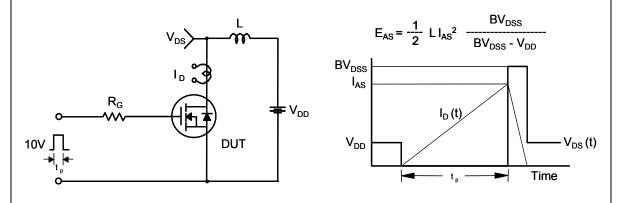
Gate Charge Test Circuit & Waveform



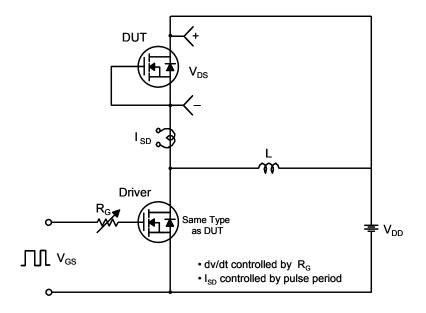
Resistive Switching Test Circuit & Waveforms

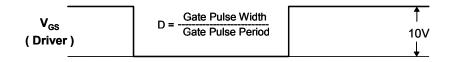


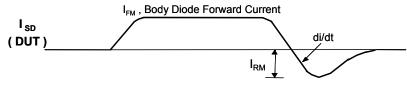
Unclamped Inductive Switching Test Circuit & Waveforms



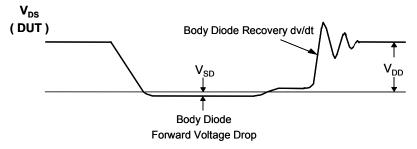
Peak Diode Recovery dv/dt Test Circuit & Waveforms





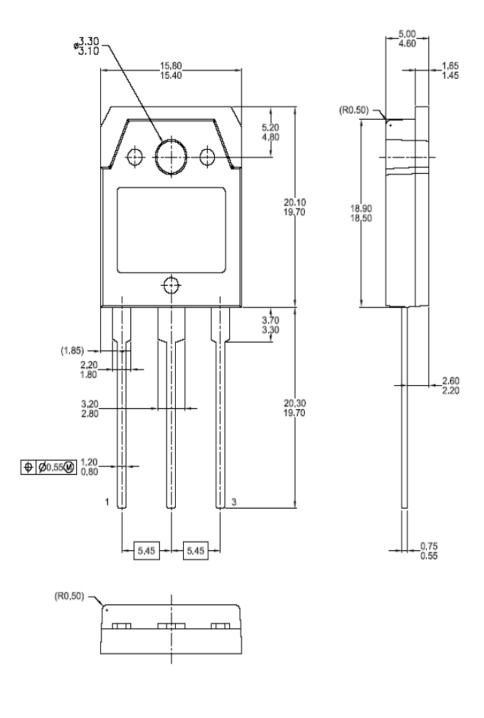


Body Diode Reverse Current



Mechanical Dimensions

TO-3PN



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